Rare-Event Simulation of Regenerative Systems: Estimation of the Mean and Distribution of Hitting Times

Bruno Tuffin

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Based on joint works with P. L'Ecuyer, P. Glynn and M. Nakayama

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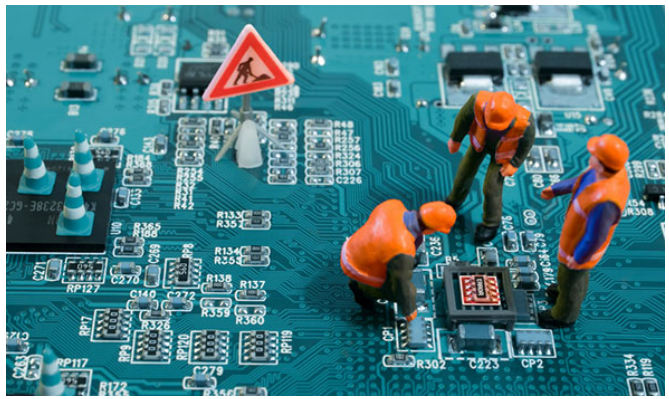
Outline

Introduction: rare events and dependability

- In *telecommunication networks*: loss probability of a small unit of information (a packet, or a cell in ATM networks), connectivity of a set of nodes,
- in *dependability analysis*: probability that a system is failed at a given time, availability, mean-time-to-failure,
- in *air control systems*: probability of collision of two aircrafts,
- in *particle transport*: probability of penetration of a nuclear shield,
- in *biology*: probability of some molecular reactions,
- in *insurance*: probability of ruin of a company,
- in *finance*: value at risk (maximal loss with a given probability in a predefined time),
- ...

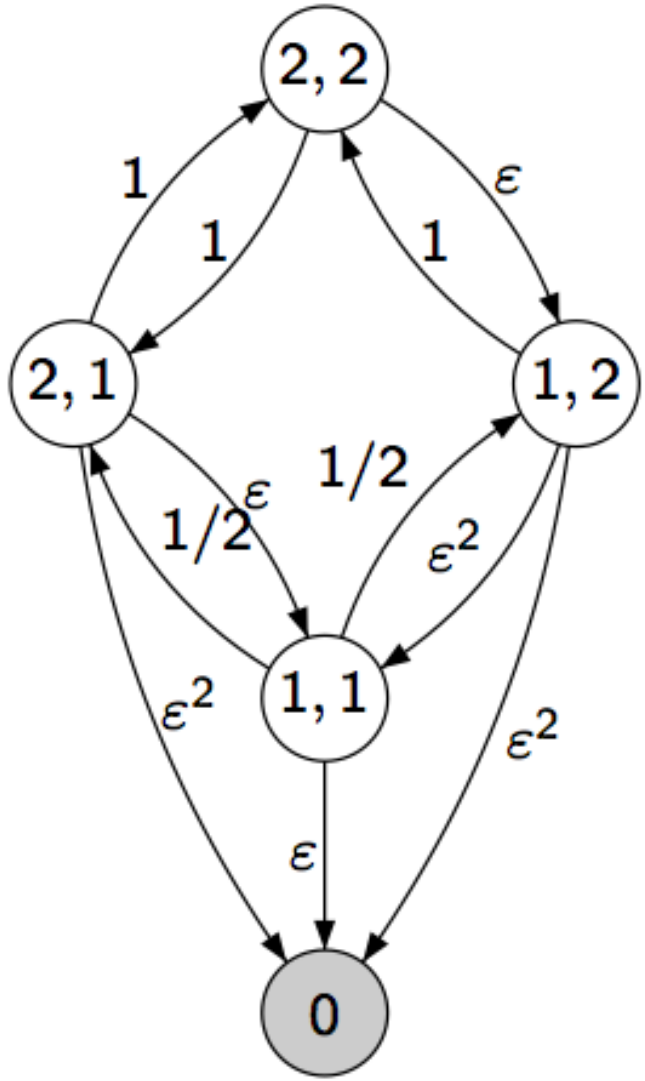
Context: Time To Failure (TTF) estimation

- Dependability analysis is of primary importance in many areas
  - nuclear power plants
  - telecommunications
  - manufacturing
  - transport systems
  - computer science
- Focus on the time to failure (TTF): random time to reach failure
- Even for Markov chains, models usually so large
  $\Rightarrow$ computation by simulation



Example: Highly Reliable Markovian Systems (HRMS)

- System with c types of components. $X = (S_1, \ldots, X_c)$ with X_i number of up components.
- Markov chain. Failure rates are $O(\varepsilon)$, but not repair rates. Failure propagations possible.
- System down when in grey state(s)
- Goal:
  - compute p probability from $(2,2)$ to hit failure before being back $(2,2)$: small if ε small.
  - compute TTF: long time if ε small.



$\mathcal{S}$-valued regenerative process $X = (X(t) : t \geq 0)$

- Goal: Compute $\alpha = \mathbb{E}[T]$, where

$$T = \inf\{t \geq 0 : X(t) \in \mathcal{A}\}$$

is the hitting time of subset $\mathcal{A}$

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- Regeneration times $0 = \Gamma(0) < \Gamma(1) < \cdots$,
  with iid cycles $((\tau(k), (X(\Gamma(k-1)+s) : 0 \leq s < \tau(k)) : k \geq 1)$
- $\tau(k) = \Gamma(k) - \Gamma(k-1)$, length of the kth regenerative cycle

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Ratio expression: $\alpha = \dfrac{\mathbb{E}[T \wedge \tau]}{\mathbb{P}(T < \tau)}$.

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Ratio expression: $\alpha = \dfrac{\mathbb{E}[T \wedge \tau]}{\mathbb{P}(T < \tau)}$.

$$\begin{aligned}
\alpha &= \mathbb{E}[T; T < \tau] + \mathbb{E}[\tau + T - \tau; T > \tau] \\
&= \mathbb{E}[T; T < \tau] + \mathbb{E}[\tau; T > \tau] + \mathbb{E}[T - \tau; T > \tau] \\
&= \mathbb{E}[T \wedge \tau; T < \tau] + \mathbb{E}[T \wedge \tau; T > \tau] + \mathbb{E}[T - \tau \mid T > \tau]\,\mathbb{P}(T > \tau) \\
&= \mathbb{E}[T \wedge \tau] + \alpha(1 - \mathbb{P}(T < \tau))
\end{aligned}$$

Regenerative simulation

- $W(k) = \inf\{t \geq 0 : X(\Gamma(k-1)+t) \in \mathcal{A}\}$ first hitting to $\mathcal{A}$ after regeneration $\Gamma(k-1)$
- $I(k) = \mathcal{I}(W(k) < \tau(k))$ with $\mathcal{I}(\cdot)$ is the indicator function

Definition (Ratio estimator)

$$\hat{\alpha}(n) = \frac{(1/n)\sum_{k=1}^{n}[W(k) \wedge \tau(k)]}{(1/n)\sum_{k=1}^{n} I(k)}.$$

Proposition (Central Limit Theorem)

$$n^{1/2}[\hat{\alpha}(n) - \alpha] \Rightarrow \sigma_2 \mathcal{N}(0,1)$$

as $n \to \infty$, *where* $\sigma_2^2 = \frac{\mathbb{E}[(T \wedge \tau)^2]}{p^2} - 2\alpha\frac{\mathbb{E}[T\mathcal{I}(T<\tau)]}{p^2} + \frac{\alpha^2}{p}$.

Rare events: hitting $\mathcal{A}$ rarely occurs before τ

- Denominator p in $\alpha = \frac{\mathbb{E}[T \wedge \tau]}{\mathbb{P}(T<\tau)}$ a small probability
  $\Longrightarrow$ requires an acceleration technique
- Fraction β of cycles used to estimate the numerator with crude MC
- Fraction $1-\beta$ to estimate the denominator with a variance reduction technique

Inefficiency of crude Monte Carlo for the denominator

- Compute the denominator/probability $p = \mathbb{E}[1_{[T<\tau]}] << 1$
- n iiid Y_i Bernoulli r.v.: 1 if the event is hit and 0 otherwise.
- To get a single occurence, we need in average $1/p$ replications (10^9 for $p = 10^{-9}$), and more to get a confidence interval.
- In most cases, you will get $(0, 0)$ as a confidence interval.
- $n\bar{Y}_n$ Binomial with parameters (n, p) and the confidence interval is

$$\left(\bar{Y}_n - \frac{c_\beta \sqrt{p(1-p)}}{\sqrt{n}}, \ \bar{Y}_n + \frac{c_\beta \sqrt{p(1-p)}}{\sqrt{n}} \right).$$

- *Relative half width* $c_\beta \sigma/(\sqrt{n}p) = c_\beta \sqrt{(1-p)/p/n} \to \infty$ as $p \to 0$.
- For a given relative error RE , the required value of

$$n = (c_\beta)^2 \frac{1-p}{RE^2 p},$$

  inversely proportional to p.
- Two main families of techniques:
  - Splitting (also called *subset simulation*) and Importance Sampling.

Robustness properties

- In rare-event simulation models, we often parameterize with a rarity parameter $\epsilon > 0$ such that $\mu = \mathbb{E}[Y(\epsilon)] \to 0$ as $\epsilon \to 0$.
- An estimator $Y(\epsilon)$ is said to have *bounded relative variance* (or *bounded relative error*) if $\sigma^2(Y(\epsilon))/\mu^2(\epsilon)$ is bounded uniformly in ϵ.
  - Interpretation: estimating $\mu(\epsilon)$ with a given relative accuracy can be achieved with a bounded number of replications even if $\epsilon \to 0$.
- Weaker property: *asymptotic optimality* (or *logarithmic efficiency*) if $\lim_{\epsilon \to 0} \ln(\mathbb{E}[Y^2(\epsilon)])/\ln(\mu(\epsilon)) = 2$.
- Stronger property: *vanishing relative variance*: $\sigma^2(Y(\epsilon))/\mu^2(\epsilon) \to 0$ as $\epsilon \to 0$. Asymptotically, we get the zero-variance estimator.
- Other robustness measures exist (based on higher degree moments, on the Normal approximation, on simulation time...).

L'Ecuyer, Blanchet, T., Glynn, ACM ToMaCS 2010

Importance Sampling (IS)

- Let $Y = h(X)$ for some function h where Y obeys some probability law $\mathbb{P}$.
- IS replaces $\mathbb{P}$ by another probability measure $\tilde{\mathbb{P}}$, using

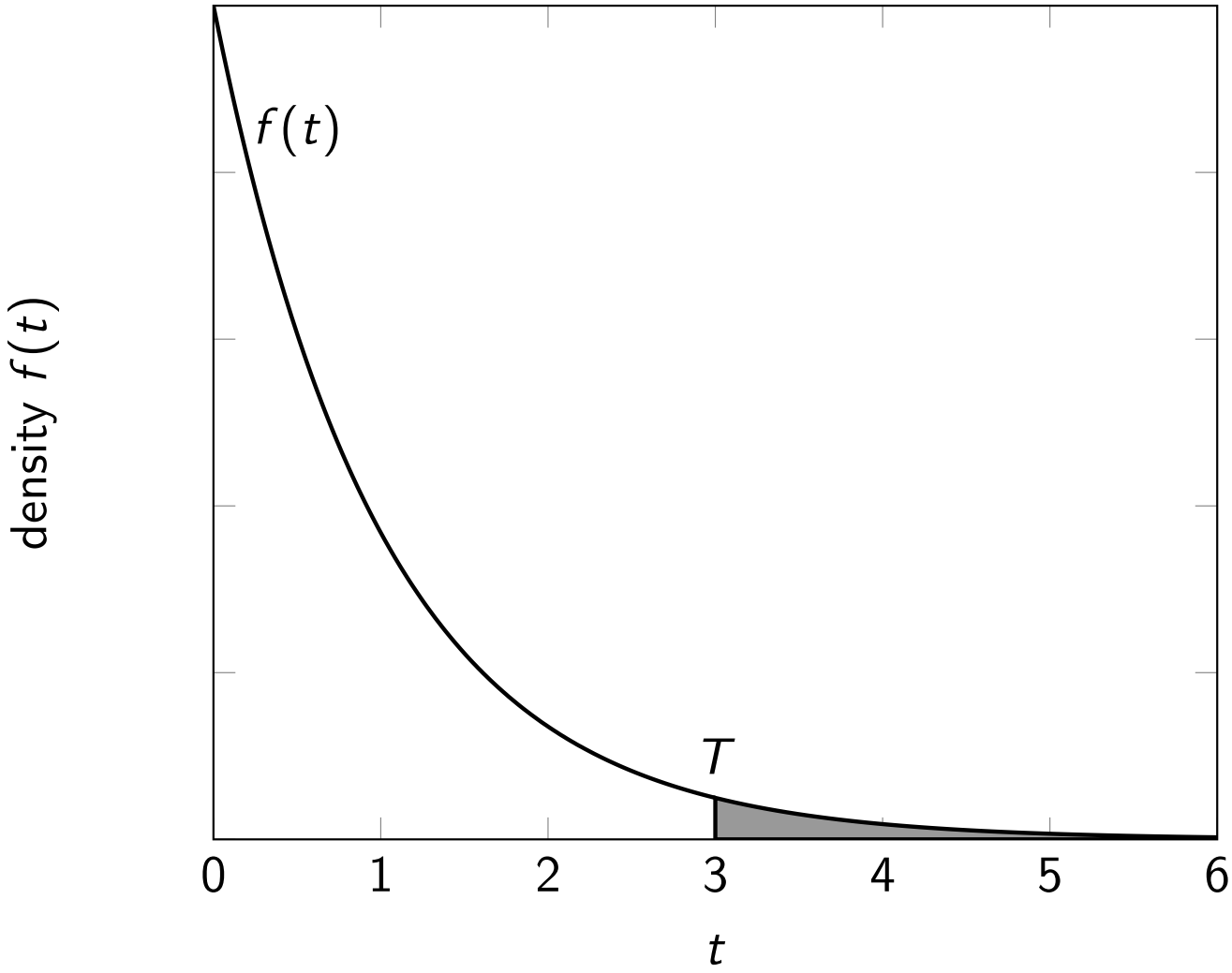
$$E[Y] = \int h(x) d\mathbb{P}(x) = \int h(x) \frac{d\mathbb{P}(x)}{d\tilde{\mathbb{P}}(x)} d\tilde{\mathbb{P}}(x) = \tilde{\mathbb{E}}\left[h(x)L(x)\right]$$

  - $L = d\mathbb{P}/d\tilde{\mathbb{P}}$ likelihood ratio,
  - $\tilde{\mathbb{E}}$ is the expectation associated to probability law $\mathbb{P}$.
- Required condition: $d\tilde{\mathbb{P}}(x) \neq 0$ when $h(x)d\mathbb{P}(x) \neq 0$.
- Unbiased estimator: $\frac{1}{n}\sum_{i=1}^{n} h(X_i)L(X_i)$ with $(X_i,\, 1 \leq i \leq n)$ i.i.d; copies of X, according to $\tilde{\mathbb{P}}$.
- Goal: select probability law $\tilde{\mathbb{P}}$ such that

$$\tilde{\sigma}^2[h(X)L(X)] = \tilde{\mathbb{E}}[(h(X)L(X))^2] - \mu^2 < \sigma^2[h(X)].$$

Example

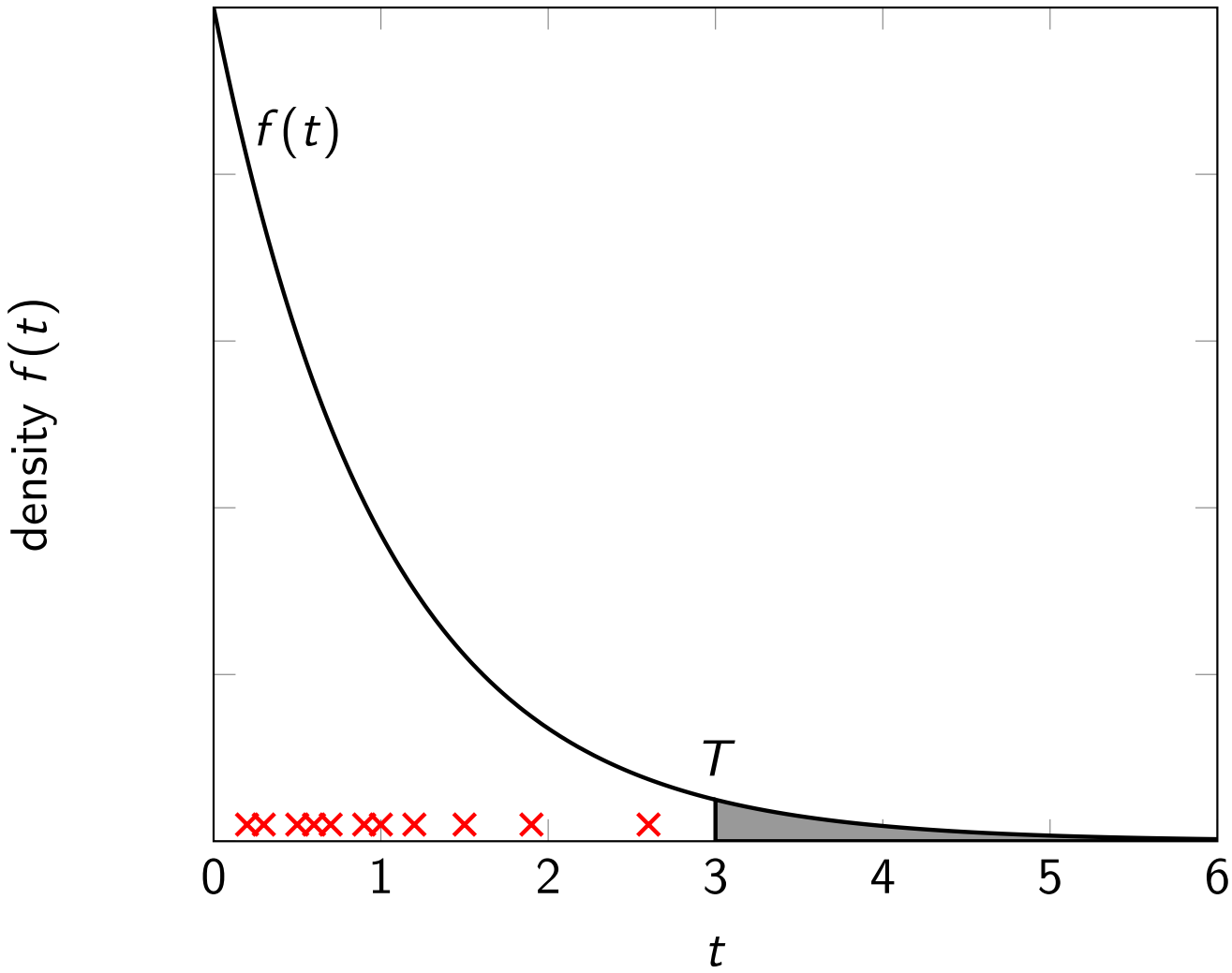
- We want to estimate the probability that a random variable exceeds T (area in grey under the density $f(t)$).



Reminder: the probability to be in an interval $[a, b]$ is the measure of the area

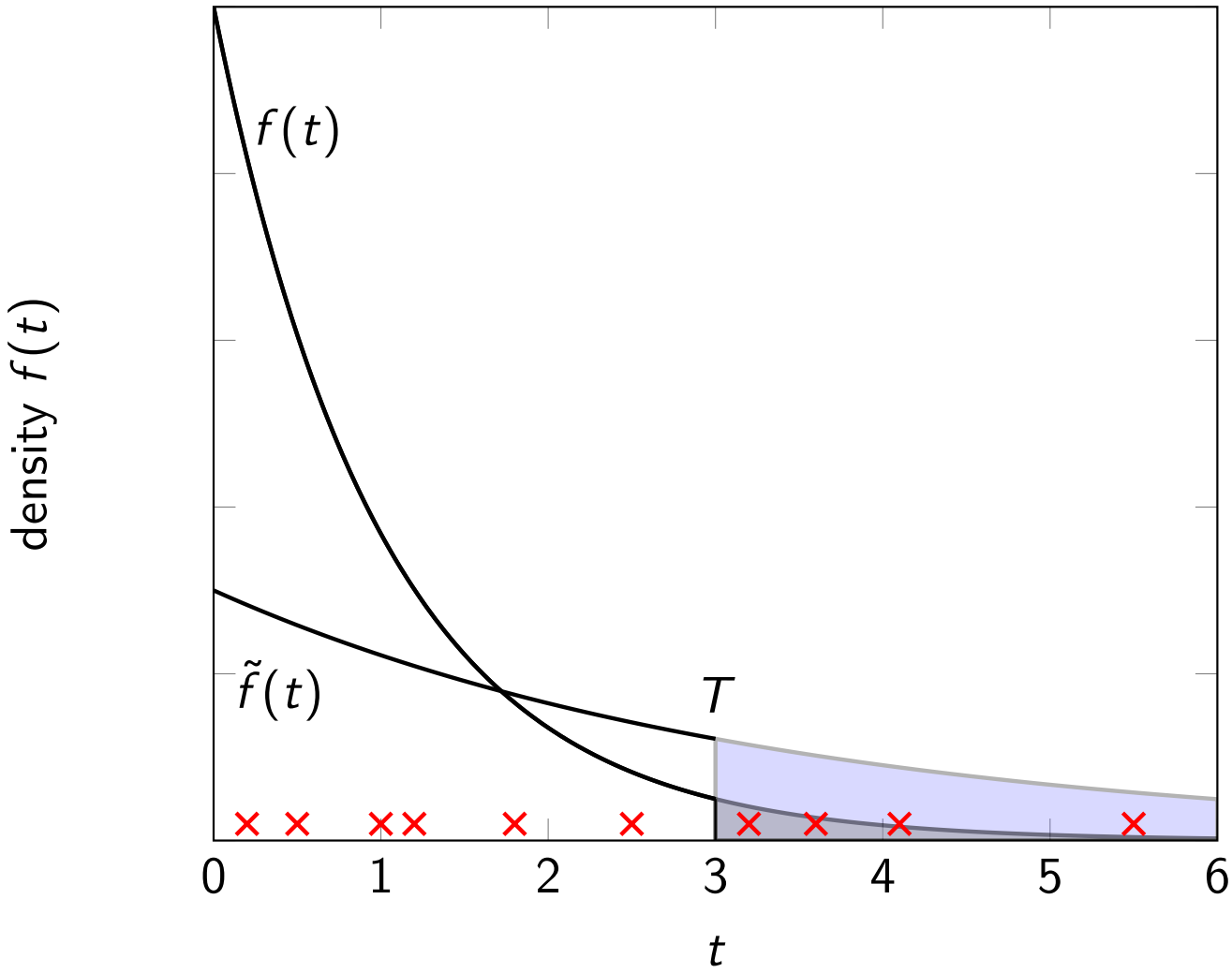
Rare event problem

- Draw values t_i (the red crosses X on the t-axis) according to density f
- Very few points (none) are $> T$.



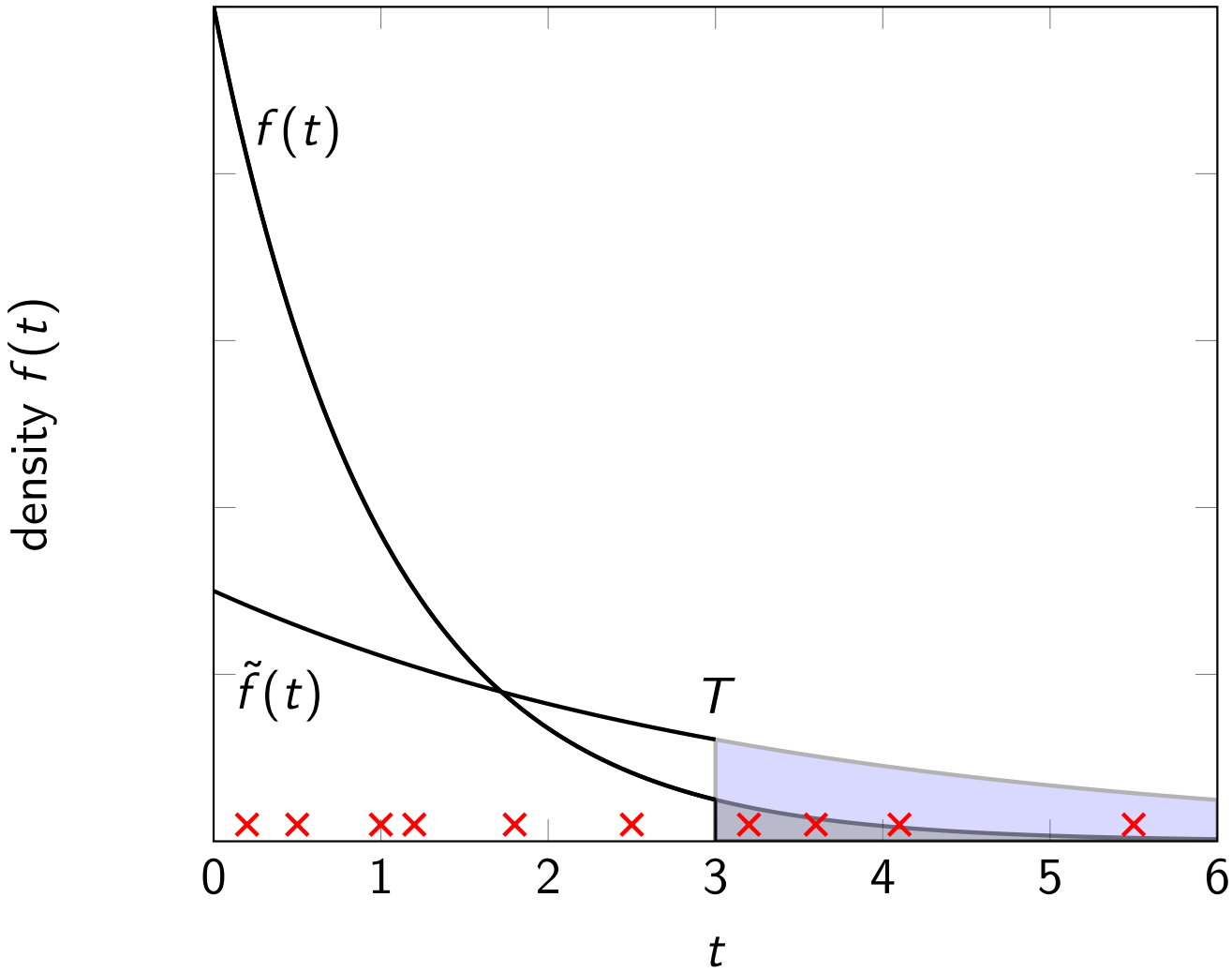
Importance sampling

- Sample according to another density $\tilde{f}$ increasing the probability to be $> T$.



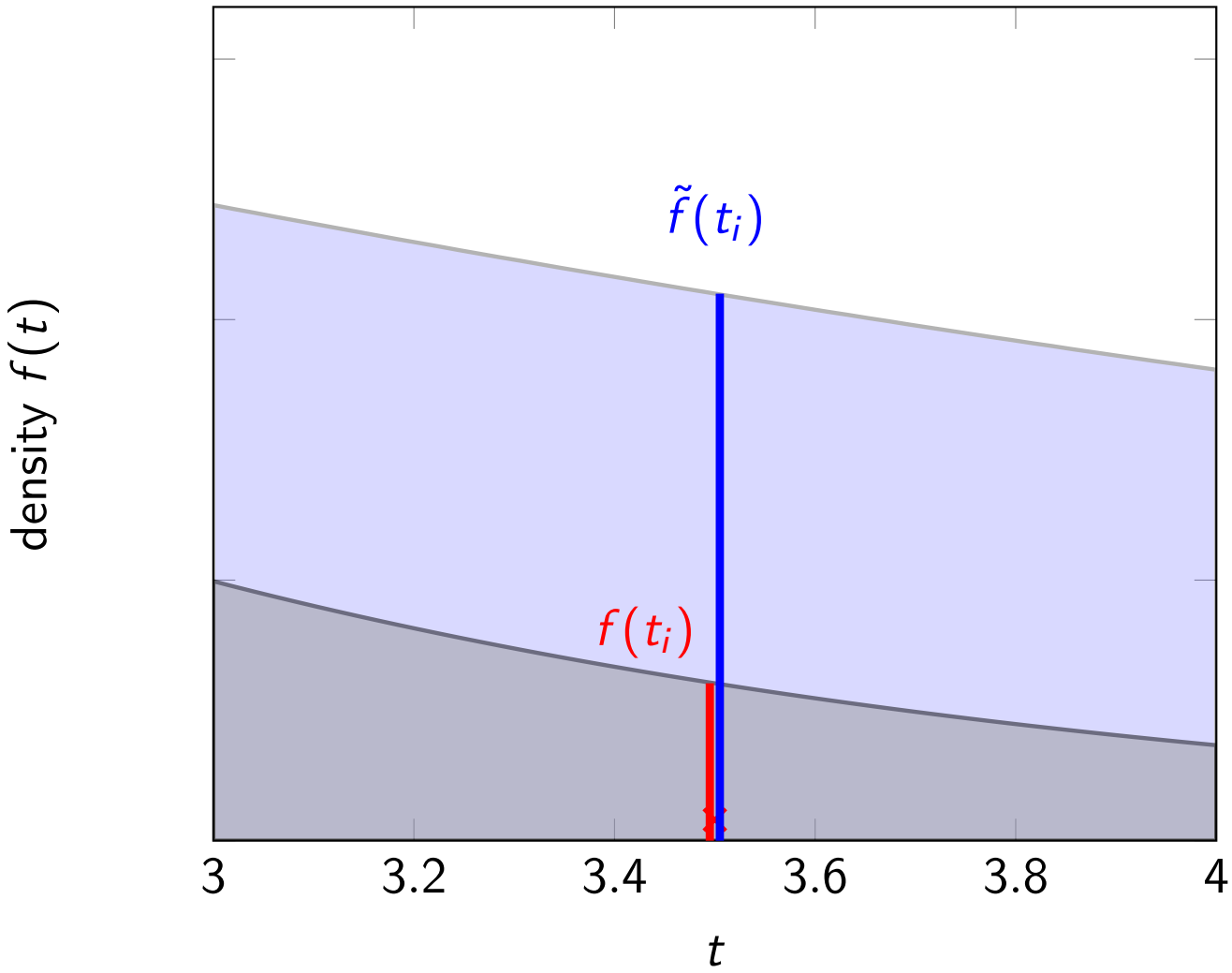
Importance sampling

- Sample according to another density $\tilde{f}$ increasing the probability to be $> T$.
- Rare set reached!



- Biased estimated probability then:
  - i.e., the proportion of points is the probability under the new density does not correspond to the grey area, but to the blue one.
- How to obtain a "valid" estimation?

- Instead of counting 1 each time we are $> T$ and look at the average value
- for each sample value t_i, we count $1(t_i > T)\frac{f(t_i)}{\tilde{f}(t_i)}$ (ratio of heights under densities at t_i) and look again at the average value
  $\Rightarrow$ unbiased estimation: the true probability is estimated.



IS for a discrete-time Markov chain (DTMC) $\{X_j, j \geq 0\}$

- $Y = h(X_0, \ldots, X_T)$ function of the sample path with
  - $P = (P(x,z))_{x,z \in \mathcal{S}}$ transition matrix, $\pi_0(x) = \mathbb{P}[X_0 = x]$, initial probabilities
  - up to a stopping time T
  - $\mu(x) = \mathbb{E}_x[Y]$.
- IS replaces the probabilities of paths $(x_0, \ldots, x_n)$,

$$\mathbb{P}[(X_0, \ldots, X_T) = (x_0, \ldots, x_n)] = \pi_0(x_0) \prod_{j=1}^{n-1} P(x_{j-1}, x_j),$$

  by $\tilde{\mathbb{P}}[(X_0, \ldots, X_T) = (x_0, \ldots, x_n)]$ st $\tilde{\mathbb{E}}[T] < \infty$.
- For convenience, the IS measure remains a DTMC, replacing $P(x,z)$ by $\tilde{P}(x,z)$ and $\pi_0(x)$ by $\tilde{\pi}_0(x)$.
- Then $L(X_0, \ldots, X_T) = \dfrac{\pi_0(X_0)}{\tilde{\pi}_0(X_0)} \displaystyle\prod_{j=1}^{T-1} \frac{P(X_{j-1}, X_j)}{\tilde{P}(X_{j-1}, X_j)}$.

Zero-variance IS estimator for Markov chains simulation

- Restrict to an additive (positive) cost

$$Y = \sum_{j=1}^{T} c(X_{j-1}, X_j)$$

  - For hitting proba: $c(x,z) = 1$ if $z \in \mathcal{A}$, 0 otherwise, $\mu(x) \equiv p(x)$
  - For hitting time: $c(x,z)$ avg time in x.
- Is there a Markov chain change of measure yielding zero-variance?
- We have zero variance with

$$\begin{aligned} \tilde{P}(x,z) &= \frac{P(x,z)(c(x,z)+\mu(z))}{\sum_w P(x,w)(c(x,w)+\mu(w))} \\ &= \frac{P(x,z)(c(x,z)+\mu(z))}{\mu(x)}. \end{aligned}$$

- Implementing it requires knowing $\mu(x)\ \forall x \in \mathcal{S}$, the quantities we wish to compute.

Zero-variance approximation

- Use a heuristic approximation $\hat{\mu}(\cdot)$ and plug it into the zero-variance change of measure instead of $\mu(\cdot)$

$$\tilde{P}(y,z) \quad = \quad \frac{P(y,z)(c(y,z)+\hat{\mu}(z))}{\sum_w P(y,w)(c(y,w)+\hat{\mu}(w))}$$

Outline

1. A short tutorial on rare-event simulation for reg. systems
2. IS application: simulation of highly reliable Markovian systems
3. Mean Time To Failure (MTTF) estimation by simulation: direct or regenerative estimator?
   - Crude estimations
   - Comparison of crude estimators
   - Importance Sampling estimators
4. Quantiles and tail-distribution measures
   - Definitions
   - Exponential approximation and associated estimators
   - Numerical examples

Highly Reliable Markovian Systems (HRMS)

- System with c types of components. $X = (X_1, \ldots, X_c)$ with X_i number of up components.
- $\mathbf{1}$: state with all components up.
- Failure rates are $O(\varepsilon)$, but not repair rates. Failure propagations possible.
- System down (in $\mathcal{A}$) when some combinations of components are down.
- Goal: compute $\mu(\mathbf{1}) \equiv p(\mathbf{1})$ with $p(y)$ probability to hit $\mathcal{A}$ before $\mathbf{1}$ starting from y (denominator of the ratio est. of MTTF)
- Simulation using the embedded DTMC. Failure probabilities are $O(\varepsilon)$ (except from $\mathbf{1}$). How to improve (accelerate) this?
- Existing method: $\forall y \neq \mathbf{1}$, increase the probability of the set of failures to constant $0.5 < q < 0.9$ and use individual probabilities proportional to the original ones (SFB), or uniformly (BFB).
- Failures not rare anymore. BRE property verified for BFB.

HRMS Example, and IS

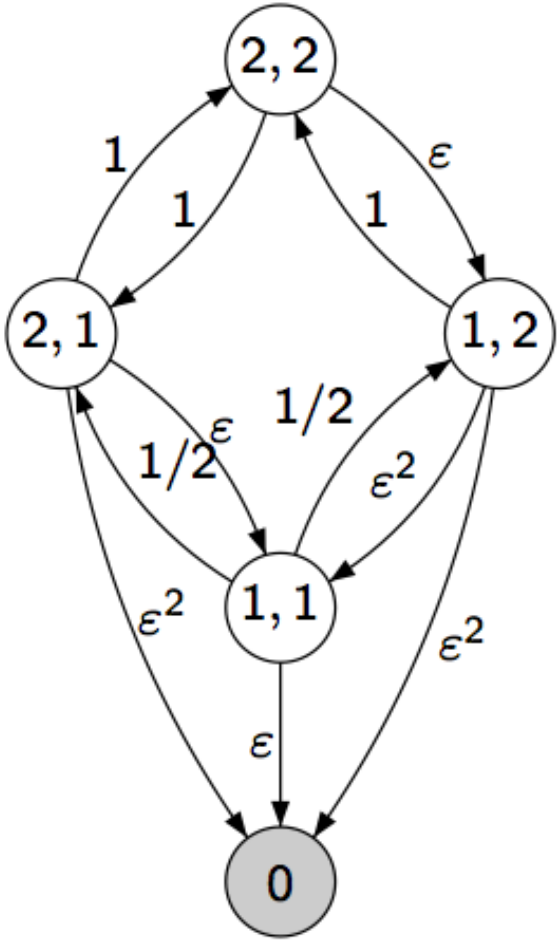


Figure: Original probabilities

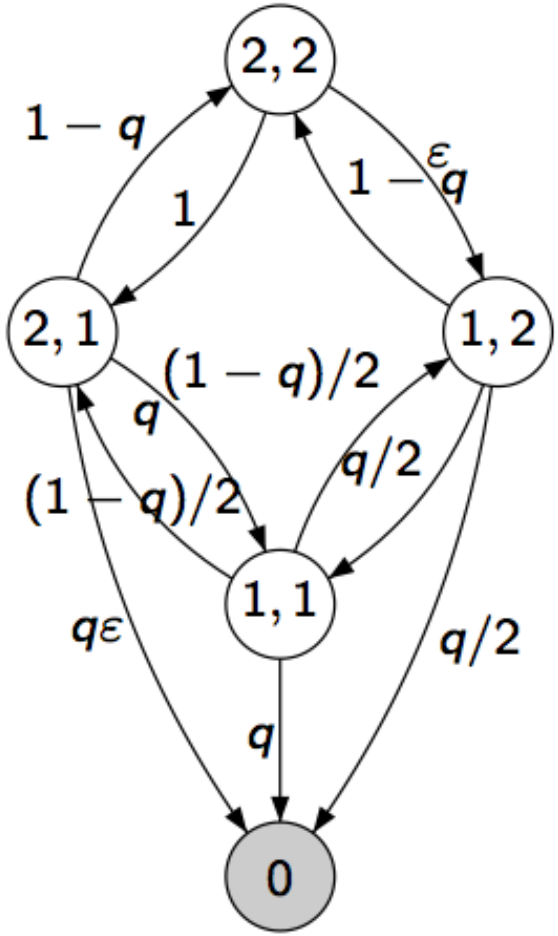


Figure: Probabilities under IS/BFB

HRMS, Zero-variance IS

L'Ecuyer & T., ANOR, 2011

- Recall the zero-variance approximation:

$$\tilde{P}(x,z) \quad = \quad \frac{P(x,z)(c(x,z)+\hat{p}(z))}{\sum_w P(y,w)(c(x,w)+\hat{p}(w))}$$

- The idea is to approach $p(y)$ by the probability $\hat{p}(y)$ of the path from y to $\mathcal{A}$ with the largest probability
- Intuition: as $\epsilon \to 0$, we get a good idea of the probability.

Proposition

Bounded Relative Error proved (as $\epsilon \to 0$) in general.
Even Vanishing Relative Error if $\hat{p}(y)$ contains all the paths with the smallest degree in ϵ.

- Other simple version: approach $p(y)$ by the (sum of) probability of paths from y with only failure components of a given type.
- Gain of several orders of magnitudes + stability of the results with respect to the literature.

HRMS: numerical illustrations

- Comparison of BFB and Zero-Variance Approximation (ZVA).
- $c = 3$ types of components, n_i of type i
- failure rates ε, 1.5ε, and $2\varepsilon^2$, repair rate 1
- System is down whenever fewer than two components of any one type are operational.

n_i	ε	μ_0	BFB est	ZVA est	BFB σ^2	ZVA σ^2
3	0.001	2.6×10^{-3}	2.7×10^{-3}	2.6×10^{-3}	6.2×10^{-5}	2.2×10^{-8}
6	0.01	1.8×10^{-7}	1.9×10^{-7}	1.8×10^{-7}	6.3×10^{-11}	2.0×10^{-14}
6	0.001	1.7×10^{-11}	1.8×10^{-11}	1.7×10^{-11}	8.8×10^{-19}	1.2×10^{-23}
12	0.1	6.0×10^{-8}	4.8×10^{-8}	6.0×10^{-8}	8.1×10^{-10}	1.6×10^{-10}
12	0.001	3.9×10^{-28}	(1.8×10^{-40})	3.9×10^{-28}	(3.2×10^{-74})	1.4×10^{-55}

Outline

Main ideas

Glynn, Nakayama & T., WSC, 2017

- Two potential estimators:
  - Direct estimator: repeat experiments up to failure of the system, and compute the average value
  - Literature, regenerative estimator: expresses the MTTF as a ratio of quantities over regenerative cycles

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- Question: Is there a reason why the regenerative estimator is used? Which one is "better"?

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  - Literature, regenerative estimator: expresses the MTTF as a ratio of quantities over regenerative cycles
- Question: Is there a reason why the regenerative estimator is used? Which one is "better"?
- Contributions
  - Crude (direct and regenerative) estimators are asymptotically similar in performance, in rare event settings
  - For Importance Sampling estimators, the regenerative one yield a efficient estimator when the crude can not.

Crude estimators of MTTF

- Notations for an S-valued regenerative process $X = (X(t) : t \geq 0)$
  - Compute $\alpha = \mathbb{E}[T]$, where $T = \inf\{t \geq 0 : X(t) \in \mathcal{A}\}$ is the hitting time of subset $\mathcal{A}$

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  - Regeneration times $0 = \Gamma(0) < \Gamma(1) < \cdots$, with iid cycles $((\tau(k), (X(\Gamma(k-1)+s) : 0 \leq s < \tau(k)) : k \geq 1)$
  - $\tau(k) = \Gamma(k) - \Gamma(k-1)$, length of the kth regenerative cycle
  - $W(k) = \inf\{t \geq 0 : X(\Gamma(k-1)+t) \in \mathcal{A}\}$ first hitting to $\mathcal{A}$ after regeneration $\Gamma(k-1)$
  - $I(k) = \mathcal{I}(W(k) < \tau(k))$ with $\mathcal{I}(\cdot)$ is the indicator function

Crude estimators of MTTF

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  - $I(k) = \mathcal{I}(W(k) < \tau(k))$ with $\mathcal{I}(\cdot)$ is the indicator function
- Ratio expression: $\alpha = \dfrac{\mathbb{E}[T \wedge \tau]}{\mathbb{P}(T < \tau)}$.

Definition

Direct estimator $\alpha_1(m) = \dfrac{1}{m} \sum_{j=1}^{m} T(j)$.

Ratio estimator $\alpha_2(n) = \dfrac{(1/n) \sum_{k=1}^{n} [W(k) \wedge \tau(k)]}{(1/n) \sum_{k=1}^{n} I(k)}$.

(Known) Central limit theorems

If $p = \mathbb{P}(T < \tau) > 0$:

Proposition (Direct estimator)

$$m^{1/2}[\alpha_1(m) - \alpha] \Rightarrow \sigma_1 \mathcal{N}(0,1)$$

as $m \to \infty$, *where*

$$\sigma_1^2 = \alpha^2 + \frac{\mathbb{E}[(T \wedge \tau)^2]}{p} - 2\alpha \frac{\mathbb{E}[T\mathcal{I}(T < \tau)]}{p}.$$

Proposition (Ratio-based estimator)

$$n^{1/2}[\alpha_2(n) - \alpha] \Rightarrow \sigma_2 \mathcal{N}(0,1)$$

as $n \to \infty$, *where*

$$\sigma_2^2 = \frac{\mathbb{E}[(T \wedge \tau)^2]}{p^2} - 2\alpha \frac{\mathbb{E}[T\mathcal{I}(T < \tau)]}{p^2} + \frac{\alpha^2}{p}.$$

Question: which estimator is "more efficient"?

- Estimators $\alpha_1(m)$ and $\alpha_2(n)$ are actually very similar
- If $N(j) = \inf\{k > N(j-1) : I(k) = 1\}$ index k of the cycle corresponding to the jth cycle in which A is hit

Proposition

For $m \geq 1$, we have $\alpha_2(N(m)) = \alpha_1(m)$.

- Is an estimator more efficient than the other?

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Proposition

For $m \geq 1$, we have $\alpha_2(N(m)) = \alpha_1(m)$.

- Is an estimator more efficient than the other?
- Two asymptotic settings
  - Decreasing reachable sets: sequence $(\mathcal{A}_b : b \geq 1)$ of subsets of S for which $p_b \equiv \mathbb{P}(T_b < \tau) \to 0$ as $b \to \infty$
  - Highly reliable systems: fixed $\mathcal{A}$ but transitions decomposed between failures and repairs with failures getting more and more rare (index ϵ) with respect to repairs

Asymptotic result with a decreasing sequence of reachable sets

- Let $\hat{\alpha}_{1,b}(c)$ and $\hat{\alpha}_{2,b}(c)$ be the estimators obtained after c units of computational time
- To hope for consistency and CLTs, we need a computational budget t_b for which $t_b p_b \to \infty$ as $b \to \infty$

Theorem (Both estimators asymptotically identical)

Assume $\mathbb{E}[\tau^3] < \infty$. *If* $t_b p_b \to \infty$ *as* $b \to \infty$, *then we have that as* $b \to \infty$,

$$\sqrt{t_b p_b}\left(\frac{\hat{\alpha}_{i,b}(t_b)}{\mathbb{E}[T_b]} - 1\right) \Rightarrow \sqrt{\mathbb{E}[\tau]}\mathcal{N}(0,1), \quad i = 1,2, \quad \textit{and}$$

$$\sqrt{t_b p_b}\left(\frac{\hat{\alpha}_{1,b}(t_b)}{\mathbb{E}[T_b]} - \frac{\hat{\alpha}_{2,b}(t_b)}{\mathbb{E}[T_b]}\right) \Rightarrow 0.$$

Numerical results for HRMS

System with 3 component types, with $n_i = 3$, failure rates ε, repair rates 1, and system is down whenever fewer than two components of any one type are operational.
Direct:

m	ϵ	Confidence Interval	Variance	CPU	Work Norm. Var.
10^7	0.1	(8.764e+00 , 8.774e+00)	5.879e+01	17.7	1.0e-04
10^7	0.01	(5.838e+02 , 5.845e+02)	3.343e+05	134	4.5e+00
10^7	0.001	(5.581e+04 , 5.588e+04)	3.117e+09	1316.5	4.1e+05

Regenerative :

n	ϵ	Confidence Interval	Variance	CPU	Work Norm. Var.
10^7	0.1	(8.762e+00 , 8.782e+00)	2.484e+02	4.283	1.1e-04
10^7	0.01	(5.788e+02 , 5.837e+02)	1.586e+07	2.917	4.6e+00
10^7	0.001	(5.459e+04 , 5.611e+04)	1.510e+12	2.800	4.2e+05

Numerical results for HRMS

System with 3 component types, with $n_i = 3$, failure rates ε, repair rates 1, and system is down whenever fewer than two components of any one type are operational.
Direct:

m	ϵ	Confidence Interval	Variance	CPU	Work Norm. Var.
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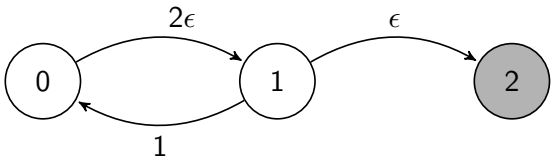
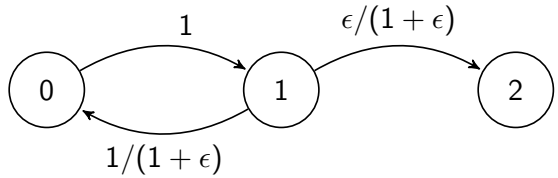
- Similar asymptotic performance
- Direct estimator: bounded relative variance, but computational time issue
- Regenerative estimator: rather a rare event issue.

- Efficient Regenerative IS estimators extensively studied.
- Question:

  What about the direct estimator?
  Can its combination with IS yield an efficient estimator?
- We will play with the toy example:



with embedded DTMC



$$\mathbb{E}_\epsilon(T_\epsilon) = \sum_{n=0}^{\infty}(n+1)\left(\frac{1}{2\epsilon}+\frac{1}{1+\epsilon}\right)\left(\frac{1}{1+\epsilon}\right)^n\frac{\epsilon}{1+\epsilon} = \frac{1+3\epsilon}{2\epsilon^2}$$

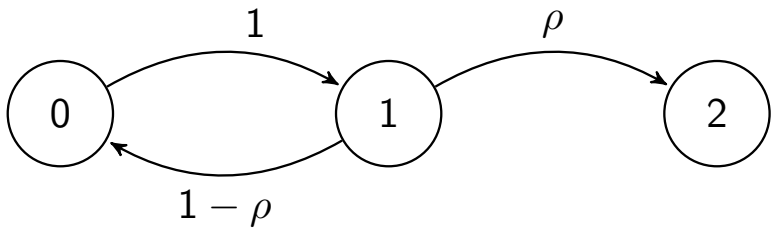
$$\mathbb{E}_\epsilon[(T_\epsilon)^2] = \sum_{n=0}^{\infty}(n+1)^2\left(\frac{1}{2\epsilon}+\frac{1}{1+\epsilon}\right)^2\left(\frac{1}{1+\epsilon}\right)^n\frac{\epsilon}{1+\epsilon} = \frac{(2+\epsilon)(1+3\epsilon)^2}{4(1+\epsilon)\epsilon^4}$$

$$\mathbb{E}_\epsilon(N) = \sum_{n=0}^{\infty}(2+2n)\left(\frac{1}{1+\epsilon}\right)^n\frac{\epsilon}{1+\epsilon} = \frac{2(1+\epsilon)}{\epsilon}$$

with N:# transitions in a run.

Failure biasing

- Change the probability of making a failure transition to be ρ, independent of ϵ



- $\tilde{\mathbb{E}}_\epsilon[(T_\epsilon L)^2] = \mathbb{E}_\epsilon[(T_\epsilon)^2 L] = \sum_{n=0}^{\infty}(n+1)^2\left(\frac{1}{2\epsilon}+\frac{1}{1+\epsilon}\right)^2 \frac{\left(\left(\frac{1}{1+\epsilon}\right)^n \frac{\epsilon}{1+\epsilon}\right)^2}{(1-\rho)^n\rho}$

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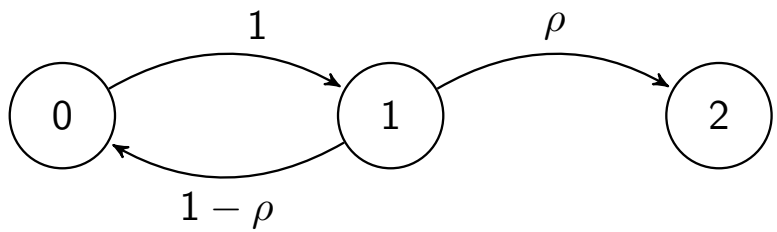

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- Converging sum iff $1/((1+\epsilon)^2(1-\rho)) < 1$, i.e., ρ small enough

$$\rho < 1 - \frac{1}{(1+\epsilon)^2} = 2\epsilon - 3\epsilon^2 + o(\epsilon^2).$$

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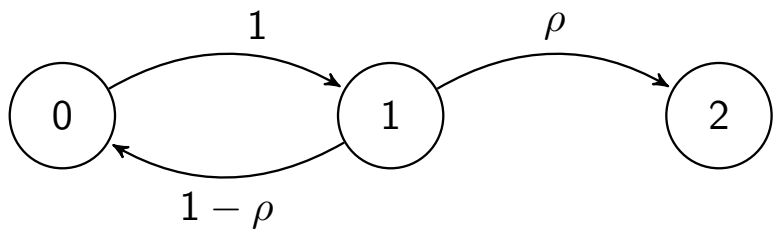

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- But $\tilde{\mathbb{E}}_\epsilon(N) = \sum_{n=0}^{\infty}(2+2n)(1-\rho)^n\rho = \frac{2}{\rho}$.

  The average simulation time for a single run will increase to infinity as $\epsilon \to 0$!

Zero-variance approximation

- For a CTMC with transition matrix $(P_{x,y})_{x,y\in S}$, if $\mathbb{E}_{\epsilon,x}$ expectation starting from x,

$$\tilde{P}_{x,y} = P_{x,y} \frac{1/\lambda(x) + \mathbb{E}_{\epsilon,y}(T_\epsilon)}{\mathbb{E}_{\epsilon,x}(T_\epsilon)}$$

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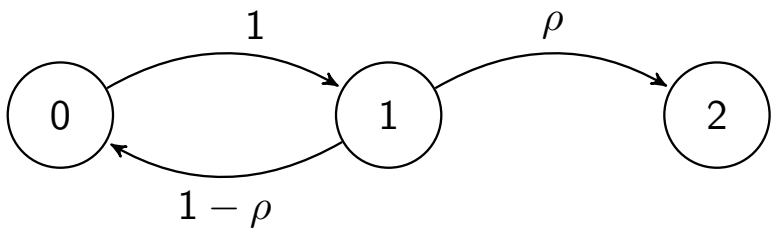
- On our toy example, the only probability we can change is from 1



- $\rho = \dfrac{\epsilon}{1+\epsilon} \dfrac{\frac{1}{1+\epsilon} + 0}{\frac{1+2\epsilon}{2\epsilon^2}} = \dfrac{2\epsilon^3}{(1+\epsilon)^2(1+2\epsilon)}$ yields variance 0.

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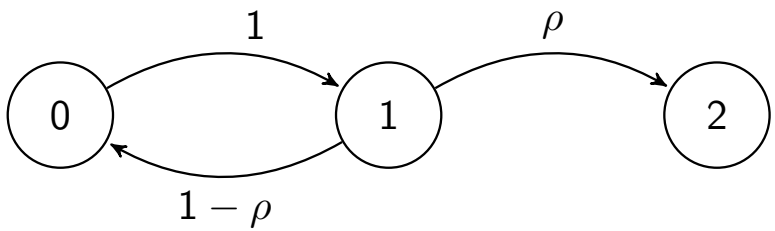

- $\rho = \dfrac{\epsilon}{1+\epsilon}\dfrac{\frac{1}{1+\epsilon}+0}{\frac{1+2\epsilon}{2\epsilon^2}} = \dfrac{2\epsilon^3}{(1+\epsilon)^2(1+2\epsilon)}$ yields variance 0.
- But the estimation takes on average longer time, $\frac{2}{\rho} = \Theta(\epsilon^{-3})$, as ϵ gets closer to zero.
- An approximation of the zero-variance IS can be inefficient, producing an unbounded work-normalized relative variance.

Discussion on the impact of the approximation

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Much better than an exact first-order approximation is required.
Hard to obtain in practice.

Conclusions on MTTF estimation

We have compared two standard estimators of the MTTF for regenerative processes

- a direct one expressed as the average of simulated times to failure
- one making use of the regenerative structure

1. Crude direct and ratio-based estimators are asymptotically equivalent (in two asymptotic contexts)
2. When IS is used, the regenerative expression is rather advised.

Outline

1. A short tutorial on rare-event simulation for reg. systems
2. IS application: simulation of highly reliable Markovian systems
3. Mean Time To Failure (MTTF) estimation by simulation: direct or regenerative estimator?
   - Crude estimations
   - Comparison of crude estimators
   - Importance Sampling estimators
4. Quantiles and tail-distribution measures
   - Definitions
   - Exponential approximation and associated estimators
   - Numerical examples

Basic idea

- Let F be the cumulative distribution function of T
- Goal: For fixed $0 < q < 1$, estimate the q-quantile ($0 < q < 1$)

$$\xi = F^{-1}(q) \equiv \inf\{t : F(t) \geq q\}$$

and the *conditional tail expectation* (CTE)

$$\gamma = E[T \mid T > \xi].$$

- Assumption: X is (classically) regenerative
with $0 = \Gamma_0 < \Gamma_1 < \Gamma_2 < \cdots$ sequence of regeneration times

Decomposition

- Using $\tau_i = \Gamma_i - \Gamma_{i-1}$ and M the number of first cycles not reaching $\mathcal{A}$

$$T = \sum_{i=1}^{M} \tau_i + T_{M+1}$$

with $T_i = \inf\{t \geq 0 : X(\Gamma_{i-1} + t) \in \mathcal{A}\}$ time to the next hit to $\mathcal{A}$ after Γ_{i-1}.

- M geometric r.v. with $P(M = k) = p(1-p)^k$ where

$$p = P(T < \tau).$$

- Recall that the regenerative structure of X allows to express

$$\alpha = E[T] = \frac{E[T \wedge \tau]}{p} \equiv \frac{\zeta}{p}.$$

Asymptotic regimes/exponential approximation

- Introduction of a rarity parameter ϵ
- Assumption: $p \equiv p_\epsilon \to 0$ as $\epsilon \to 0$.
  - Ex HRMS: Probability of reaching a failed state before coming back to the initial (perfectly working) state goes to 0 with failure rates
  - Ex GI/G/1 queue: considering a receding set of states (number of customers) $\mathcal{A} \equiv \mathcal{A}_\epsilon = \{b_\epsilon, b_\epsilon + 1, b_\epsilon + 2, \ldots\}$.

Theorem (Known result)

The scaled hitting time $T_\epsilon/\alpha_\epsilon$ converges weakly to an exponential: for each $x \geq 0$,

$$P_\epsilon(T_\epsilon/\alpha_\epsilon \leq x) \to 1 - e^{-x} \text{ as } \epsilon \to 0.$$

Quantile and CTE estimators based on the exponential approximation

From

$$F(t) = P(T \leq t) = P(T/\alpha \leq t/\alpha) \approx 1 - e^{-t/\alpha} \equiv \widetilde{F}_{\exp}(t),$$

we get

- $\widetilde{\xi}_{\exp} = \widetilde{F}^{-1}_{\exp}(q) = -\alpha \ln(1-q)$
- $\widetilde{\gamma}_{\exp} = \widetilde{\xi}_{\exp} + \alpha = \alpha[1 - \ln(1-q)]$.

Using the ZVA efficient estimator $\widehat{\alpha}$ of α, we get

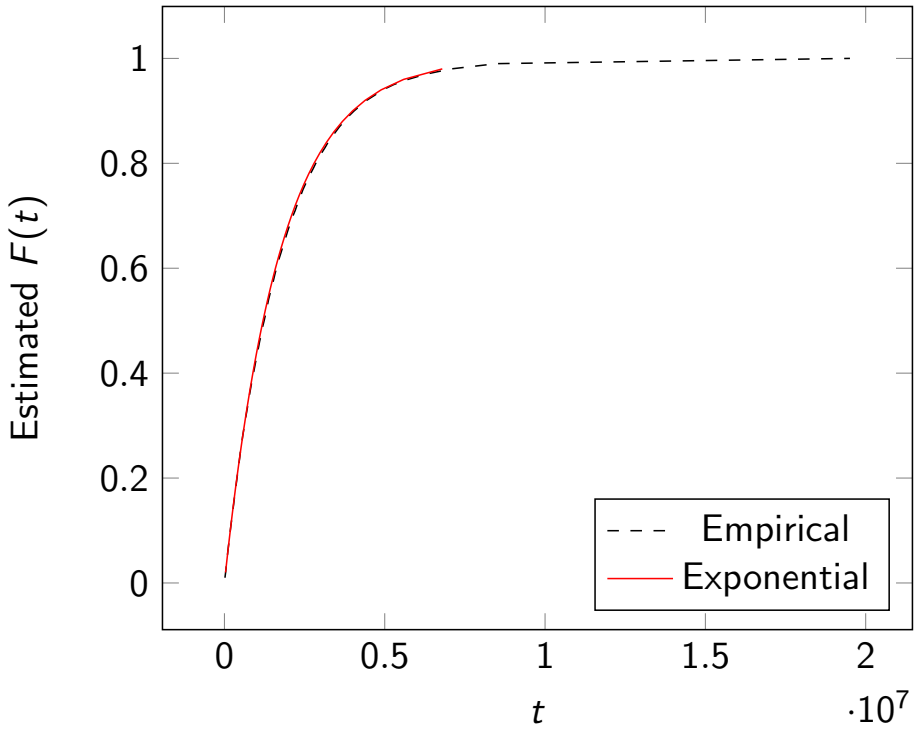
$$\widehat{\xi}_{\exp} = \widehat{F}^{-1}_{\exp}(q) = -\widehat{\alpha} \ln(1-q) \text{ and } \widehat{\gamma}_{\exp} = \widehat{\xi}_{\exp} + \widehat{\alpha} = \widehat{\alpha}[1 - \ln(1-q)]$$

- Efficient estimators
- ...but biased
- Other more involved estimators available in our WSC'2018 paper.

Numerical example

- HRMS with three component types
- five components of each type
- 15 repairmen
- system up whenever at least two components of each type work
- Each component has failure rate ϵ and repair rate 1.

With $\epsilon = 10^{-2}$



Numerical results

- Quantile estimators

ϵ	q	Empirical 95% CI	CPU	Expon. Est.	Expon. 95% CI	CPU
0.01	0.1	(1.701e+05, 1.971e+05)	890 sec	1.830e+05	(1.764e+05, 1.896e+05)	0.3 sec
0.01	0.5	(1.206e+06, 1.271e+06)	890 sec	1.204e+06	(1.161e+06, 1.247e+06)	0.3 sec
0.01	0.9	(3.958e+06, 4.135e+06)	890 sec	4.000e+06	(3.856e+06, 4.143e+06)	0.3 sec
10^{-4}	0.1	N/A	N/A	1.757e+13	(1.756e+13, 1.758e+13)	0.3 sec
10^{-4}	0.5	N/A	N/A	1.155e+14	(1.154e+14, 1.157e+14)	0.3 sec
10^{-4}	0.9	N/A	N/A	3.840e+14	(3.838e+14, 3.842e+14)	0.3 sec

- CTE estimators

ϵ	q	Empir. Est.	CPU	Expon. Est.	Expon. 95% CI	CPU
0.01	0.1	1.964e+06	890 sec	1.920e+06	(1.851e+06, 1.989e+06)	0.3 sec
0.01	0.5	3.011e+06	890 sec	2.941e+06	(2.836e+06, 3.046e+06)	0.3 sec
0.01	0.9	5.915e+06	890 sec	5.737e+06	(5.531e+06, 5.942e+06)	0.3 sec
10^{-4}	0.1	N/A	N/A	1.839e+14	(1.834e+14, 1.845e+14)	0.3 sec
10^{-4}	0.5	N/A	N/A	2.817e+14	(2.809e+14, 2.826e+14)	0.3 sec
10^{-4}	0.9	N/A	N/A	5.495e+14	(5.479e+14, 5.512e+14)	0.3 sec

  - Very efficient
  - But biased.... for small ϵ, does not *seem* a problem in practice
  - Other less biased estimators studied in our WSC'2018 paper.

References

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